L	Hits	Search Text	DB	Time stamp
Number	6217	inapatt(and (F) attented in argame()	HCDAT.	2003/12/11
_	021/	inspect\$4 and (Electron adj microscop\$4)	USPAT; US-PGPUB	12:10
_	6615	inspect\$4 and (Electron adj microscop\$4)	USPAT;	2003/12/11
	}	I	US-PGPUB;	12:10
	I	1	EPO;	
_	4638	(inspect\$4 and (Electron adj	USPAT;	2003/12/11
		microscop\$4)) and layer\$3	US-PGPUB;	12:10
İ		l	EPO;	
	471	 ((inspect\$4 and (Electron adj	DERWENT USPAT;	2003/12/11
- 	!	microscop\$4)) and layer\$3) and untreat\$3	US-PGPUB;	12:10
	i	and treat\$4	EPO;	
			DERWENT	!
· -	0	"09820143"	USPAT; US-PGPUB;	2003/12/11 12:10
	j	1	US-PGPUB; EPO;	12:10
	İ		DERWENT	
–	į 798		USPAT;	2003/12/11
!		microscop\$4)) and layer\$3) and	US-PGPUB;	12:10
I		((untreat\$3 and treat\$4) or (expos\$3 and unexpos\$3) or (radiat\$3 and unradiat\$3))	EPO; DERWENT	1
_	640		USPAT;	2003/12/11
		microscop\$4)) and layer\$3) and	US-PGPUB;	12:10
· · I		((untreat\$3 same treat\$4) or (expos\$3	EPO;	1
I	ļ	same unexpos\$3) or (radiat\$3 same unradiat\$3))	DERWENT	!
_	169	1	USPAT;	2003/12/11
}	1	microscop\$4)) and layer\$3) and	US-PGPUB;	12:10
<u> </u> 		((untreat\$3 same treat\$4) or (expos\$3	EPO;	
		same unexpos\$3) or (radiat\$3 same unradiat\$3))) and photoresist\$3	DERWENT	
_	1 24	okoroanyanwu.in.	USPAT;	2003/12/11
	i		US-PGPUB;	12:10
			EPO;	
!	101	singh-bhanwar.in.	DERWENT USPAT;	2003/12/11
_	181	· Singn-Dhanwar.in. i	US-PGPUB;	12:10
	i		EPO;	
			DERWENT	
! _ :	0	acheta-alden.in.	USPAT; US-PGPUB;	2003/12/11
		1	EPO;	12.10
	! 		DERWENT	į
! -	725		USPAT;	2003/12/11
!		! (integrat\$3 adj circuit\$3)	US-PGPUB; EPO;	12:11
			DERWENT	
_	543	(layer\$3 and flood\$3 and photoresist\$3	USPAT;	2003/12/11
		and (integrat\$3 adj circuit\$3)) and	US-PGPUB;	12:11
<u> </u>		region	EPO; DERWENT	
 _	1 473	<pre>: ((layer\$3 and flood\$3 and photoresist\$3</pre>	USPAT;	2003/12/11
	1	and (integrat\$3 adj circuit\$3)) and	US-PGPUB;	12:11
	İ	region) and reduc\$5	EPO;]
!		1	DERWENT	2002/12/11
-	; 96	<pre>(((layer\$3 and flood\$3 and photoresist\$3 and (integrat\$3 adj circuit\$3)) and</pre>	USPAT; US-PGPUB;	2003/12/11
	! J	region) and reduc\$5) and inspec\$5	EPO;	
I 			DERWENT	i
_ i	279838	inspect\$4 amd electron and (electron adj	USPAT;	2003/12/11
	İ	microscop\$2) and (integrated adj circuit)	US-PGPUB; EPO;	12:11
) 	1		DERWENT	
: <u>-</u>	11801	(inspect\$4 amd electron and (electron adj	USPAT;	2003/12/11
İ	1	microscop\$2) and (integrated adj	US-PGPUB;	12:11
	1	circuit)) and layer and surface and	EPO;	ļ
<u> </u>		transform\$	DERWENT	<u></u>

			- 	
_	766	((inspect\$4 amd electron and (electron	USPAT;	2003/12/11
	1	adj microscop\$2) and (integrated adj	US-PGPUB;	12:11
	; ;	circuit)) and layer and surface and	EPO;	
	!	transform\$) and ((enclos\$3 or	DERWENT	·
ļ	İ	encapsulat\$3) near4 (surface or layer))	DERWENT	i
		- I	TTC D B III -	2002 (12 (11
_	52	(((inspect\$4 amd electron and (electron	USPAT;	2003/12/11
!		adj microscop\$2) and (integrated adj	US-PGPUB;	12:11
I	i	circuit)) and layer and surface and	EPO;	
į		transform\$) and ((enclos\$3 or	DERWENT	1
:		encapsulat\$3) near4 (surface or layer)))		i
	!			•
	:	and photoresist	L TIODAM.	2003/12/11
-	567	(shell or (cross adj link\$4)) and	USPAT;	
	,	(barrier or trap\$4) and layer and	US-PGPUB;	12:11
!		outgas\$4	EPO;	
i		-	DERWENT	
; _	929 1	<pre>inspect\$3 and (integrat\$3 adj circuit)</pre>	USPAT;	2003/12/11
i	727	and (electron adj microscop\$2) and	US-PGPUB	12:11
	·		OD-FGFOD	12.11
		electron and beam		10000 470 473
1 -	211	(inspect\$3 and (integrat\$3 adj circuit)	USPAT;	2003/12/11
	į l	and (electron adj microscop\$2) and	US-PGPUB	12:11
İ		electron and beam) and ((treat\$4 or		
i	1	transform\$5) same surface)		
•	1 1 1	(inspect\$3 and (integrat\$3 adj circuit)	USPAT;	2003/12/11
i	1 72 ;			12:11
	; i	and (electron adj microscop\$2) and	US-PGPUB	14:11
	1	electron and beam) and ((treat\$4 or	 	
1	, l	transform\$5) same surface same ("SEM" or		!
1	į į	microscop\$2) same inspect\$4)	}	1
: _	794		USPAT;	2003/12/11
i	194	bitocorestschi same (nannie of siteti)	US-PGPUB	12:11
1				
-	120	<pre>(photoresist\$4 same (bubble or shell))</pre>	USPAT;	2003/12/11
	!	and electron and microscop\$2	_i US-PGPUB	12:11
-	2240	250/310	USPAT;	2003/12/11
			US-PGPUB	12:11
!	1714	250/311	USPAT;	2003/12/11
-	1/14	230/311	•	12:11
!	!		US-PGPUB	· .
-	2553	250/306	USPAT;	2003/12/11
	1		US-PGPUB	12:11
_	2158	250/307	USPAT;	2003/12/11
			US-PGPUB	12:11
I	426	(250/310 or 250/311 or 250/306 or	USPAT;	2003/12/11
	420	250/307) and photoresist\$4	US-PGPUB	12:11
İ				2003/12/11
-	368	((250/310 or 250/311 or 250/306 or	USPAT;	· · ·
	•	250/307) and photoresist\$4) and layer	US-PGPUB	12:11
-	j 95	(((250/310 or 250/311 or 250/306 or	USPAT;	2003/12/11
!	'	250/307) and photoresist\$4) and layer)	US-PGPUB	12:11
!		and electron and inspect\$4		
!	140		USPAT	2003/12/11
	149	430/16	JUERI	12:11
	•			
_	515	430/23	USPAT	2003/12/11
	:			12:11
	2097	430/30	USPAT	2003/12/11
•	1	= = · · · = =		12:11
1	1004		USPAT	2003/12/11
_	1984	i 430/296	ODENI	12:11
	· !	1	1	·
-	ⁱ 3175	430/311	USPAT	2003/12/11
1	1			12:11
· ·	1079	438/623	USPAT	2003/12/11
1	1 4019	130,023		12:11
:		1	USPAT	2003/12/11
-		400 (701	USPAI	
	653	438/701	1	
	653	438/701		12:11
_	653	438/701	USPAT	12:11 2003/12/11
_	1			
-	897	438/725	USPAT	2003/12/11 12:11
-	1	438/725 (430/16 or 430/23 or 430/30 or 430/296 or	USPAT;	2003/12/11 12:11 2003/12/11
 - -	897	438/725 (430/16 or 430/23 or 430/30 or 430/296 or 430/311 or 438/623 or 438/701 or 438/725)	USPAT	2003/12/11 12:11
-	897 5535	438/725 (430/16 or 430/23 or 430/30 or 430/296 or 430/311 or 438/623 or 438/701 or 438/725) and photoresist\$4	USPAT; USPAT; US-PGPUB	2003/12/11 12:11 2003/12/11 12:11
- - -	897	438/725 (430/16 or 430/23 or 430/30 or 430/296 or 430/311 or 438/623 or 438/701 or 438/725) and photoresist\$4 ((430/16 or 430/23 or 430/30 or 430/296	USPAT; USPAT; US-PGPUB USPAT;	2003/12/11 12:11 2003/12/11 12:11 2003/12/11
-	897 5535	438/725 (430/16 or 430/23 or 430/30 or 430/296 or 430/311 or 438/623 or 438/701 or 438/725) and photoresist\$4 ((430/16 or 430/23 or 430/30 or 430/296	USPAT; USPAT; US-PGPUB	2003/12/11 12:11 2003/12/11 12:11
-	897 5535	438/725 (430/16 or 430/23 or 430/30 or 430/296 or 430/311 or 438/623 or 438/701 or 438/725) and photoresist\$4	USPAT; USPAT; US-PGPUB USPAT;	2003/12/11 12:11 2003/12/11 12:11 2003/12/11

- 417 (((430/16 or 430/23 or 430/30 or 430/296 or 430/311 or 438/623 or 438/701 or us-pgpub 12:11 438/725) and photoresist\$4) and layer) and electron and inspect\$4 - 198 ((((430/16 or 430/23 or 430/30 or 430/296 or 430/311 or 438/623 or 438/701 or 430/311 or 438/623 or 438/701 or us-pgpub 12:11 438/725) and photoresist\$4) and layer) and electron and inspect\$4) and microscop\$2 - 57 (((inspect\$4 and (Electron adj us-pgpub; 12:11 microscop\$4)) and layer\$3) and untreat\$3 us-pgpub; 12:11 and treat\$4) and photoresist\$3 - 26 (((inspect\$4 and photoresist\$3) and untreat\$3 us-pgpub; 12:11 microscop\$4)	2/11
- 198 ((((430/16 or 430/23 or 430/30 or 430/296 USPAT; 2003/12 or 430/311 or 438/623 or 438/701 or 438/725) and photoresist\$4) and layer) and electron and inspect\$4) and microscop\$2 - 57 (((inspect\$4 and (Electron adj microscop\$4)) and layer\$3) and untreat\$3 and treat\$4) and photoresist\$3 USPAT; 2003/12 US	
and electron and inspect\$4) and microscop\$2 - 57 (((inspect\$4 and (Electron adj USPAT; 2003/12 microscop\$4)) and layer\$3) and untreat\$3 US-PGPUB; 12:11 and treat\$4) and photoresist\$3 EPO; DERWENT	2/11
- 57 (((inspect\$4 and (Electron adj USPAT; 2003/12 microscop\$4)) and layer\$3) and untreat\$3 US-PGPUB; 12:11 and treat\$4) and photoresist\$3 EPO; DERWENT	2/11
- 26 ((((inspect\$4 and (Electron adj microscop\$4)) and layer\$3) and (US-PGPUB; 12:11 ((untreat\$3 same treat\$4) or (expos\$3 same unexpos\$3) or (radiat\$3 same unradiat\$3))) and photoresist\$3) and flood\$3	2/11
- 37 (okoroanyanwu.in. or singh-bhanwar.in.) USPAT; 2003/12 and (Electron adj microscop\$4) US-PGPUB 12:11	2/11
1 ((okoroanyanwu.in. or singh-bhanwar.in.) USPAT; 2003/12 and (Electron adj microscop\$4)) and US-PGPUB 12:11 untreat\$3	2/11
- 24 (((layer\$3 and flood\$3 and photoresist\$3 USPAT; 2003/12 and (integrat\$3 adj circuit\$3)) and US-PGPUB; 12:11 region) and reduc\$5) and shell EPO; DERWENT	2/11
- 45 ((((layer\$3 and flood\$3 and photoresist\$3 USPAT; 2003/12 and (integrat\$3 adj circuit\$3)) and US-PGPUB; 12:12 region) and reduc\$5) and inspec\$5) and EPO; enclos\$3	2/11
- 59 (((inspect\$4 amd electron and (electron USPAT; 2003/12 adj microscop\$2) and (integrated adj US-PGPUB; 12:12 circuit)) and layer and surface and EPO; transform\$) and ((enclos\$3 or encapsulat\$3) near4 (surface or layer))) and photoresist\$3	2/11
((shell or (cross adj link\$4)) and USPAT; 2003/12 (barrier or trap\$4) and layer and outgas\$4) and photoresist\$4 EPO; DERWENT	2/11 i
2 5330881.pn. USPAT; 2003/12 US-PGPUB; 12:12 EPO; DERWENT	2/11
- 15 ((inspect\$3 and (integrat\$3 adj circuit) USPAT; 2003/12 and (electron adj microscop\$2) and US-PGPUB 12:12 electron and beam) and ((treat\$4 or transform\$5) same surface)) and ((treat\$4 or transform\$5) same surface same ("SEM" or microscop\$2) same inspect\$4)	2/11
- 39 ((photoresist\$4 same (bubble or shell)) USPAT; 2003/12 and electron and microscop\$2) and US-PGPUB 12:12 (flood\$3 or inspect\$4)	2/11
91 ((((250/310 or 250/311 or 250/306 or USPAT; 2003/12 250/307) and photoresist\$4) and layer) US-PGPUB 12:12 and electron and inspect\$4) and microscop\$2	2/11
- 11 (US-6143666-\$ or US-5783366-\$ or USPAT 2003/12 US-6444381-\$ or US-5510216-\$ or US-6420702-\$ or US-6589709-\$ or US-6358670-\$ or US-5928821-\$ or US-5242864-\$ or US-6121130-\$ or US-5747803-\$).did.	2/11
- 17 (((((430/16 or 430/23 or 430/30 or USPAT; 2003/12 430/296 or 430/311 or 438/623 or 438/701 US-PGPUB 12:12 or 438/725) and photoresist\$4) and layer) and electron and inspect\$4) and microscop\$2) and flood\$3	2/11

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